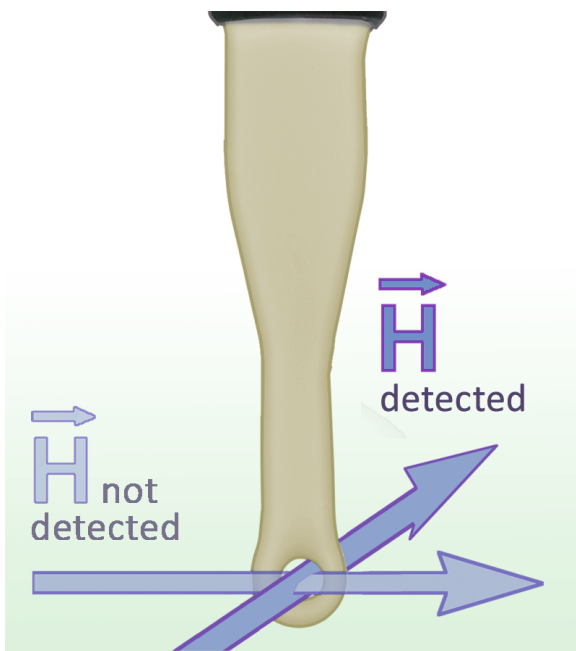


SX-R 3-1

磁场探头 (1GHz-10GHz)



Short description

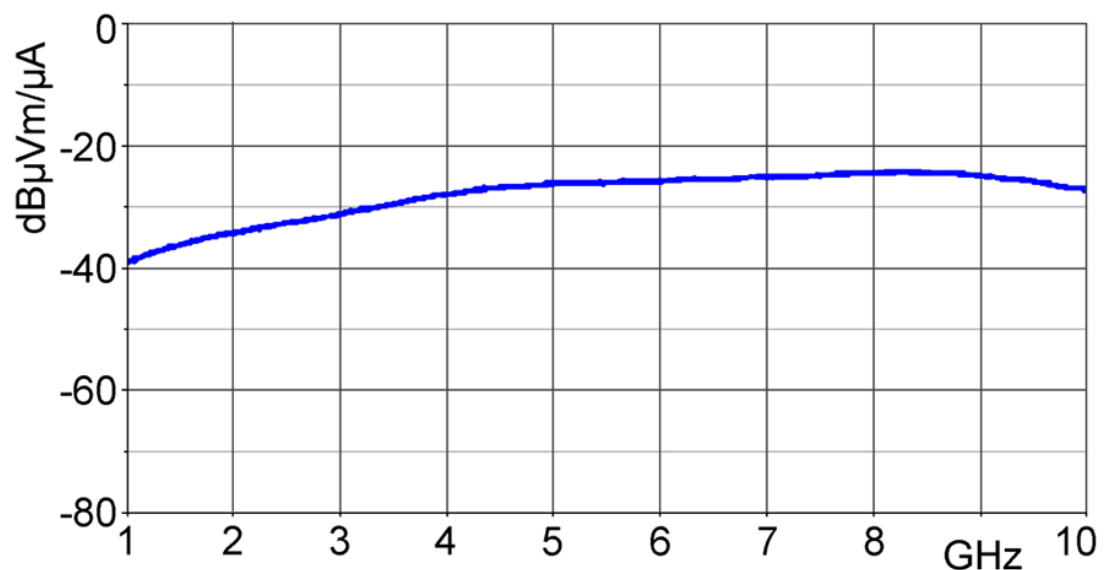
SX-R 3-1型磁场探头尺寸小，用于高分辨率测量高频磁场，因而能够识别出作为潜在干扰源的最小元件。此外，由于探头尺寸小，适于测量很难靠近的位置，例如集成电路引脚的周围区域。

The SX-R 3-1 is a passive near-field probe. The probe head is very small and therefore suitable for detection of magnetic-field distribution, e.g. at ICs. Because of its compact design, the SX-R 3-1 can be used at hard to reach spots, e.g. between components. It has a current attenuating sheath and its upper side is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input.

Technical parameters

频率范围	1 GHz ... 10 GHz
分辨率	≈ 1 mm
探头尺寸	$\varnothing \approx 3$ mm
输出接口	SMA, female, jack

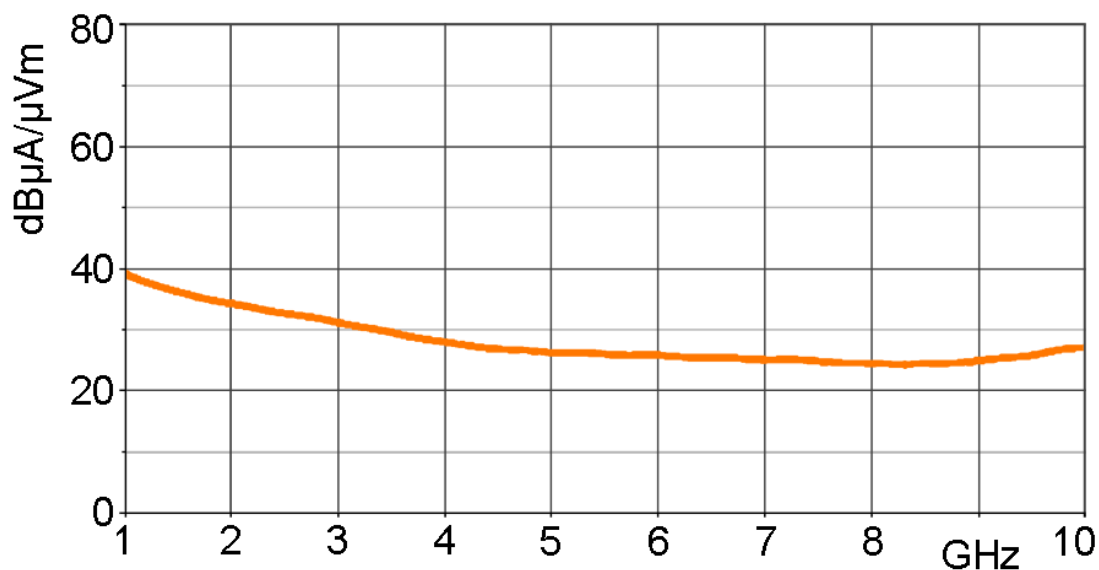
频率特性 [dB μ V] / [dB μ A/m]



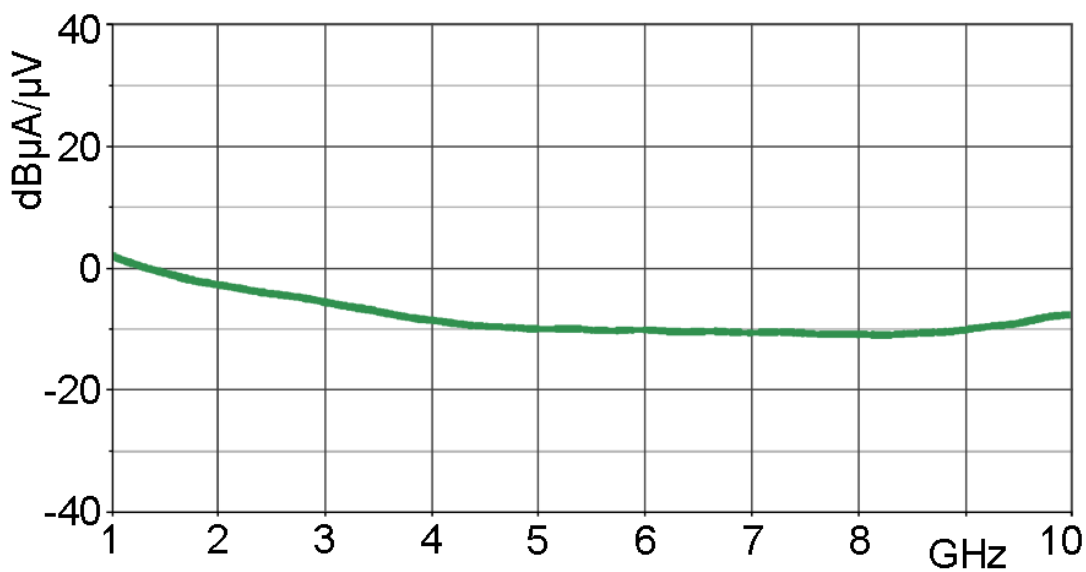
SX-R 3-1

磁场探头 (1GHz-10GHz)

磁场校正曲线 [dB μ A/m] / [dB μ V]



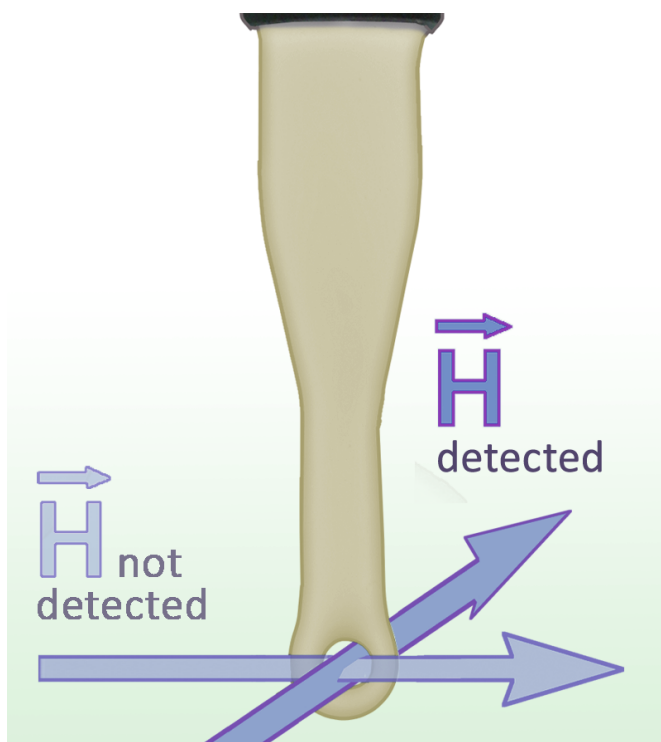
电流校正曲线 [dB μ A] / [dB μ V]



SX-R 3-1

磁场探头 (1GHz-10GHz)

LANGER
EMV-Technik



Probe head

